ELSEVIER

Journal of Non-Crystalline Solids 262 (2000) 291–292

JOURNAL OF NON-CRYSTALLINE SOLIDS

www.elsevier.com/locate/jnoncrysol

Author Index

Akai, T., Temperature dependence of Li NMR linewidth in glasses: relation between short-range ionic motion observed by NMR and long range ionic transport observed by electrical conductivity 262 (2000) 271

Aldon, L., P.E. Lippens, J.C. Jumas, J. Olivier Fourcade, H. Bemelmans and G. Langouche, Molecular structure of ternary Ge–As–Te glasses studied by Mössbauer spectroscopy 262 (2000) 244

Angermann, T., see Höche, T. 262 (2000) 114

Avramov, I., Pressure dependence of viscosity of glassforming melts 262 (2000) 258

Balkenende, A.R., see Koenderink, G.H. 262 (2000) 80

Bauer, C., R. Richert, R. Böhmer and T. Christensen, Dynamic thermal expansivity near the glass transition 262 (2000) 276

Bemelmans, H., see Aldon, L. 262 (2000) 244

Bian, X., see Zhang, L. 262 (2000) 169

Böhmer, R., see Bauer, C. 262 (2000) 276

Bratu, I., see Culea, E. 262 (2000) 287

Brzesowsky, R.H., see Koenderink, G.H. 262 (2000) 80

Buechele, A.C., see McKeown, D.A. 262 (2000) 126

Burns, A.E., M. Royle and S.W. Martin, Infrared spectroscopy of AgI doped $Ag_2S+B_2S_3$ fast ion conducting thioborate glasses 262 (2000) 252

Chen, H., C. Zhu, B. Yu, H. Lu and F. Gan, Preparation and optical properties of CuI microcrystallite-doped borosilicate glasses 262 (2000) 282

Christensen, T., see Bauer, C. 262 (2000) 276

Cortès, R., see Mastelaro, V.R. 262 (2000) 191

Culea, E. and I. Bratu, Structural and magnetic behaviour of some borate glasses containing dysprosium ions 262 (2000) 287

de Moraes, M.A.B., see Wang, J. 262 (2000) 216

Delord, P., see Dieudonné, Ph. 262 (2000) 155

Dieudonné, Ph., A. Hafidi Alaoui, P. Delord and J. Phalippou, Transformation of nanostructure of silica gels during drying 262 (2000) 155

Durrant, S.F., see Wang, J. 262 (2000) 216

Fourcade, J.O., see Aldon, L. 262 (2000) 244

Gan, F., see Chen, H. 262 (2000) 282

Garnier, A., see Rogez, J. 262 (2000) 177

Ghobarkar, H., see Rogez, J. 262 (2000) 177

Gilani, A.H., see Khattak, G.D. 262 (2000) 66

Gupta, P.K., D. Inniss, C.R. Kurkjian and Q. Zhong, Nanoscale roughness of oxide glass surfaces 262 (2000) 200

Hafidi Alaoui, A., see Dieudonné, Ph. 262 (2000) 155

Hayakawa, S. and L.L. Hench, AM1 study on infra-red spectra of silica clusters modified by fluorine 262 (2000) 264

Hench, L.L., see Hayakawa, S. 262 (2000) 264

Höche, T. and T. Angermann, Cross-sectional TEM investigation of tin-implanted SiO_2 glass 262 (2000) 114

Inniss, D., see Gupta, P.K. 262 (2000) 200

Iyetomi, H., P. Vashishta and R.K. Kalia, Incipient phase separation in Ag/Ge/Se glasses: clustering of Ag atoms 262 (2000) 135

Jin, J., S. Sakida, T. Yoko and M. Nogami, The local structure of Sm-doped aluminosilicate glasses prepared by sol–gel method 262 (2000) 183

Jumas, J.C., see Aldon, L. 262 (2000) 244

Kalia, R.K., see Iyetomi, H. 262 (2000) 135

Kendziora, C.A., see McKeown, D.A. 262 (2000) 126

Khattak, G.D., M.A. Salim, L.E. Wenger and A.H. Gilani, X-ray photoelectron spectroscopy (XPS) and magnetic susceptibility studies of copper–vanadium phosphate glasses 262 (2000) 66

Kityk, I.V., see Plucinski, K. 262 (2000) 143

Knauth, P., see Rogez, J. 262 (2000) 177

Koenderink, G.H., R.H. Brzesowsky and A.R. Balkenende, Effect of the initial stages of leaching on the surface of alkaline earth sodium silicate glasses 262 (2000) 80

0022-3093/00/$ - see front matter © 2000 Elsevier Science B.V. All rights reserved.

Kurkjian, C.R., see Gupta, P.K. 262 (2000) 200

Langouche, G., see Aldon, L. 262 (2000) 244
Leppert, V.J., see Molodetsky, I. 262 (2000) 106
Lequeux, N., see Mastelaro, V.R. 262 (2000) 191
Li, H., see Zhang, L. 262 (2000) 169
Lippens, P.E., see Aldon, L. 262 (2000) 244
Lu, H., see Chen, H. 262 (2000) 282
Lu, K., see Ye, F. 262 (2000) 228

Martin, S.W., see Burns, A.E. 262 (2000) 252
Mastelaro, V.R., E.D. Zanotto, N. Lequeux and R. Cortès, Relationship between short-range order and ease of nucleation in $Na_2Ca_2Si_3O_9$, $CaSiO_3$ and $PbSiO_3$ glasses 262 (2000) 191
McKeown, D.A., I.S. Muller, A.C. Buechele, I.L. Pegg and C.A. Kendziora, Structural characterization of high-zirconia borosilicate glasses using Raman spectroscopy 262 (2000) 126
Mefleh, A., see Plucinski, K. 262 (2000) 143
Molodetsky, I., A. Navrotsky, M.J. Paskowitz, V.J. Leppert and S.H. Risbud, Energetics of X-ray-amorphous zirconia and the role of surface energy in its formation 262 (2000) 106
Muller, I.S., see McKeown, D.A. 262 (2000) 126

Navrotsky, A., see Molodetsky, I. 262 (2000) 106
Nogami, M., see Jin, J. 262 (2000) 183

Paskowitz, M.J., see Molodetsky, I. 262 (2000) 106
Pegg, I.L., see McKeown, D.A. 262 (2000) 126
Phalippou, J., see Dieudonné, Ph. 262 (2000) 155
Plucinski, K., I.V. Kityk and A. Mefleh, Elliptically polarized light-induced second harmonic generation in SiN_xO_y 262 (2000) 143
Prentice, J.S.C., The effect of surface states at the SnO_2/p-a-Si:H interface 262 (2000) 99

Richert, R., see Bauer, C. 262 (2000) 276
Risbud, S.H., see Molodetsky, I. 262 (2000) 106
Rogez, J., P. Knauth, A. Garnier, H. Ghobarkar and O. Schäf, Determination of the crystallization enthalpies of lithium ion conducting alumino–silicate glasses 262 (2000) 177
Royle, M., see Burns, A.E. 262 (2000) 252
Rüssel, C., see von der Gönna, G. 262 (2000) 236

Sakida, S., see Jin, J. 262 (2000) 183
Salim, M.A., see Khattak, G.D. 262 (2000) 66
Schäf, O., see Rogez, J. 262 (2000) 177
Shkrob, I.A., B.M. Tadjikov and A.D. Trifunac, Magnetic resonance studies on radiation-induced point defects in mixed oxide glasses. I. Spin centers in B_2O_3 and alkali borate glasses 262 (2000) 6
Shkrob, I.A., B.M. Tadjikov and A.D. Trifunac, Magnetic resonance studies on radiation-induced point defects in mixed oxide glasses. II. Spin centers in alkali silicate glasses 262 (2000) 35
Stebbins, J.F. and Q. Zeng, Cation ordering at fluoride sites in silicate glasses: a high-resolution ^{19}F NMR study 262 (2000) 1
Swiatkowski, W., Effect of different sizes of subcritical nuclei on kinetics of transformation in the solid state 262 (2000) 162

Tadjikov, B.M., see Shkrob, I.A. 262 (2000) 6
Tadjikov, B.M., see Shkrob, I.A. 262 (2000) 35
Trifunac, A.D., see Shkrob, I.A. 262 (2000) 6
Trifunac, A.D., see Shkrob, I.A. 262 (2000) 35

Vashishta, P., see Iyetomi, H. 262 (2000) 135
von der Gönna, G. and C. Rüssel, Thermodynamics of various polyvalent elements in a $15Na_2O \cdot 85SiO_2$ glass melt 262 (2000) 236

Wang, J., S.F. Durrant and M.A.B. de Moraes, Deposition mechanisms and properties of oxygenated carbon nitride films from rf discharges of acetylene, nitrogen, oxygen and argon mixtures 262 (2000) 216
Wang, W., see Zhang, L. 262 (2000) 169
Wenger, L.E., see Khattak, G.D. 262 (2000) 66
Wirbeleit, F., A multi-variable analysis of the influence of process parameters on VHF PECVD deposition process for amorphous silicon 262 (2000) 207
Wu, S., see Zhang, L. 262 (2000) 169
Wu, Y., see Zhang, L. 262 (2000) 169

Ye, F. and K. Lu, Crystallization kinetics of Al–La–Ni amorphous alloy 262 (2000) 228
Yoko, T., see Jin, J. 262 (2000) 183
Yu, B., see Chen, H. 262 (2000) 282

Zanotto, E.D., see Mastelaro, V.R. 262 (2000) 191
Zeng, Q., see Stebbins, J.F. 262 (2000) 1
Zhang, L., Y. Wu, X. Bian, H. Li, W. Wang and S. Wu, Short-range and medium-range order in liquid and amorphous $Al_{90}Fe_5Ce_5$ alloys 262 (2000) 169
Zhong, Q., see Gupta, P.K. 262 (2000) 200
Zhu, C., see Chen, H. 262 (2000) 282

ELSEVIER

Journal of Non-Crystalline Solids 262 (2000) 293–294

JOURNAL OF NON-CRYSTALLINE SOLIDS

www.elsevier.com/locate/jnoncrysol

Subject Index

Alkali Silicate Glasses
Electrochemical Properties, Melting 262 (2000) 236
Nuclear Magnetic Resonance, Radiation Effects 262 (2000) 35

Amorphous Semiconductors
Computer Simulation, Photo Voltage, Tin Oxide 262 (2000) 99
Silicon, Thin Films 262 (2000) 207

Atomic Force Microscopy
Fracture, Surface Properties 262 (2000) 200

Borates
Infra-red Absorption 262 (2000) 252
Magnetic Properties, Rare Earth Ions 262 (2000) 287

Borosilicates
Raman Spectra, Structure, Zirconia 262 (2000) 126

Calorimetry 262 (2000) 106
Conductivity, Crystallization 262 (2000) 177

Chalcogenide Glasses
Mössbauer Effect, Structure 262 (2000) 244

Chalcogenides
Computer Simulation, Molecular Dynamics Simulation 262 (2000) 135
Crystallization, Nucleation 262 (2000) 162

Chemical Durability
Rutherford Backscattering, Secondary Ion Mass Spectroscopy, Surface Reactions 262 (2000) 80

Computer Simulation
Amorphous Semiconductors, Photo Voltage, Tin Oxide 262 (2000) 99
Chalcogenides, Molecular Dynamics Simulation 262 (2000) 135

Conductivity
Calorimetry, Crystallization 262 (2000) 177

Crystallization
Calorimetry, Conductivity 262 (2000) 177
Chalcogenides, Nucleation 262 (2000) 162
Medium-Range Order, Metallic Glasses, X-ray Diffraction 262 (2000) 169
Metallic Glasses 262 (2000) 228

Defects
Nuclear Magnetic Resonance, Radiation Effects 262 (2000) 6

Differential Scanning Calorimetry
Glass Transition 262 (2000) 276

Drying
Sol–Gel Processes, Structure 262 (2000) 155

Electrochemical Properties
Alkali Silicate Glasses, Melting 262 (2000) 236

Fluorides
Nuclear Magnetic Resonance, Structure 262 (2000) 1

Fracture
Atomic Force Microscopy, Surface Properties 262 (2000) 200

Glass Transition
Differential Scanning Calorimetry 262 (2000) 276

Infra-red Absorption
Borates 262 (2000) 252
Medium-Range Order, Silica 262 (2000) 264

Ion Implantation
Tin Oxide 262 (2000) 114

Ionic Conductivity
Nuclear Magnetic Resonance 262 (2000) 271

Magnetic Properties
Borates, Rare Earth Ions 262 (2000) 287
Phosphates, XPS 262 (2000) 66

Medium-Range Order
Crystallization, Metallic Glasses, X-ray Diffraction 262 (2000) 169
Infra-red Absorption, Silica 262 (2000) 264

Melting
Alkali Silicate Glasses, Electrochemical Properties 262 (2000) 236

Metallic Glasses
Crystallization 262 (2000) 228
Crystallization, Medium-Range Order, X-ray Diffraction 262 (2000) 169

Molecular Dynamics Simulation
Chalcogenides, Computer Simulation 262 (2000) 135

0022-3093/00/$ - see front matter © 2000 Elsevier Science B.V. All rights reserved.

Mössbauer Effect
Chalcogenide Glasses, Structure 262 (2000) 244

Nitrogen-Containing Glass
Thin Films 262 (2000) 216

Nuclear Magnetic Resonance
Alkali Silicate Glasses, Radiation Effects 262 (2000) 35
Defects, Radiation Effects 262 (2000) 6
Fluorides, Structure 262 (2000) 1
Ionic Conductivity 262 (2000) 271
Rare Earth Ions, Sol–Gel Method, Structure 262 (2000) 183

Nucleation
Chalcogenides, Crystallization 262 (2000) 162
Structure, X-ray Absorption 262 (2000) 191

Optical Properties
Oxynitride Glasses, Surface Properties 262 (2000) 143
Quantum Wells, Semiconductors 262 (2000) 282

Oxynitride Glasses
Optical Properties, Surface Properties 262 (2000) 143

Phosphates
Magnetic Properties, XPS 262 (2000) 66

Photo Voltage
Amorphous Semiconductors, Computer Simulation, Tin Oxide 262 (2000) 99

Pressure Effects
Viscosity 262 (2000) 258

Quantum Wells
Optical Properties, Semiconductors 262 (2000) 282

Radiation Effects
Alkali Silicate Glasses, Nuclear Magnetic Resonance 262 (2000) 35
Defects, Nuclear Magnetic Resonance 262 (2000) 6

Raman Spectra
Borosilicates, Structure, Zirconia 262 (2000) 126

Rare Earth Ions
Borates, Magnetic Properties 262 (2000) 287
Nuclear Magnetic Resonance, Sol–Gel Method, Structure 262 (2000) 183

Rutherford Backscattering
Chemical Durability, Secondary Ion Mass Spectroscopy, Surface Reactions 262 (2000) 80

Secondary Ion Mass Spectroscopy
Chemical Durability, Rutherford Backscattering, Surface Reactions 262 (2000) 80

Semiconductors
Optical Properties, Quantum Wells 262 (2000) 282

Silica
Infra-red Absorption, Medium-Range Order 262 (2000) 264

Silicon
Amorphous Semiconductors, Thin Films 262 (2000) 207

Sol–Gel Method
Nuclear Magnetic Resonance, Rare Earth Ions, Structure 262 (2000) 183

Sol–Gel Processes
Drying, Structure 262 (2000) 155

Structure
Borosilicates, Raman Spectra, Zirconia 262 (2000) 126
Chalcogenide Glasses, Mössbauer Effect 262 (2000) 244
Drying, Sol–Gel Processes 262 (2000) 155
Fluorides, Nuclear Magnetic Resonance 262 (2000) 1
Nuclear Magnetic Resonance, Rare Earth Ions, Sol–Gel Method 262 (2000) 183
Nucleation, X-ray Absorption 262 (2000) 191

Surface Properties
Atomic Force Microscopy, Fracture 262 (2000) 200
Optical Properties, Oxynitride Glasses 262 (2000) 143

Surface Reactions
Chemical Durability, Rutherford Backscattering, Secondary Ion Mass Spectroscopy 262 (2000) 80

Thin Films
Amorphous Semiconductors, Silicon 262 (2000) 207
Nitrogen-Containing Glass 262 (2000) 216

Tin Oxide
Amorphous Semiconductors, Computer Simulation, Photo Voltage 262 (2000) 99
Ion Implantation 262 (2000) 114

Viscosity
Pressure Effects 262 (2000) 258

XPS
Magnetic Properties, Phosphates 262 (2000) 66

X-ray Absorption
Nucleation, Structure 262 (2000) 191

X-ray Diffraction
Crystallization, Medium-Range Order, Metallic Glasses 262 (2000) 169

Zirconia
Borosilicates, Raman Spectra, Structure 262 (2000) 126